

Notice of References Cited	Application/Control No. 09/804,302	Applicant(s)/Patent Under Reexamination OTSUKA, TORU	
	Examiner Thomas H. Stevens	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,651,225	11-2003	Lin et al.	716/4
	B	US-5,363,320	11-1994	Boyle et al.	703/2
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kinoshita et al., "Application of Monte Carlo Simulation to Structural Analysis by Soft X-Ray Emission Spectroscopy for a Silicide/Si-Bulk System" 1999 Publication Board, Japanese Journal of Applied Physics. pp. 6544-6548
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.